OPA817

OPA817 800MHz、高精度、ユニティ ゲイン安定、FET 入力オペアンプ

1 特長

- 広い帯域幅:
 - ゲイン帯域幅積:400MHz
 - 帯域幅 (G = 1V/V):800MHz
 - 大信号帯域幅 (2V_{PP}):250MHz
 - スルーレート: 1000V/μs
- 高精度:
 - 入力オフセット電圧:250µV (最大値)
 - 入力オフセット電圧ドリフト:3.5µV/℃ (最大値)
- 入力電圧ノイズ:4.5nV/√Hz
- 入力バイアス電流:2pA
- 低歪み (R_L = 100Ω、V_O = 2V_{PP}):
 - 10MHz ੴ HD2、HD3:-86dBc、-100dBc
- 電源電圧範囲:6V~12.6V
- 消費電流:23.5mA
- シャットダウン電流:55µA
- OPA656 の性能アップグレード版

2 アプリケーション

- 高速データ アクイジション (DAQ)
- アクティブ プローブ
- オシロスコープ
- 広帯域のトランスインピーダンス アンプ (TIA)
- ウェハー スキャン機器
- 光通信モジュール
- 光時間領域反射測定法 (OTDR)
- テストおよび測定機器のフロントエンド
- 医療用および化学用分析器

R_{F1} $\Lambda\Lambda\Lambda$ ADS4149 THS4541 Input V_{CM} O ADC $R_{\text{G2}} \\$ V_{REF} R_{F2}

入力インピーダンスの高いデジタイザ用フロントエン

3 概要

OPA817 は、高速、高精度、広いダイナミック レンジのア プリケーションに適した、ユニティゲイン安定の電圧帰還 型オペアンプです。

OPA817 は、400MHz の広いゲイン帯域幅と 6V~12.6V の電源電圧範囲を特長とする、低ノイズ接合ゲート電界効 果トランジスタ (JFET) 入力段を備えています。1000V/μs という高速スルーレートは、高速デジタイザ、アクティブ プ ローブ、他の試験/測定機器アプリケーションで高インピ ーダンス バッファとして使用する際、広い大信号帯域幅と 低歪みを実現できます。

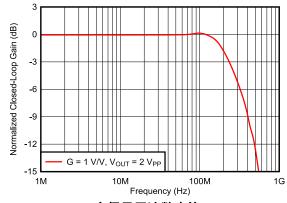
OPA817 は、入力オフセット電圧が ±250µV と非常に低 く、オフセット電圧ドリフトは ±3.5uV/℃です。 入力バイアス 電流がピコアンペア単位であり、また、入力電圧ノイズが 低い (4.5nV/√Hz) ため、OPA817 は光学テスト機器、通 信機器、医療用および科学用計測機器の広帯域トランス インピーダンスアンプとして優れた選択肢です。

OPA817 は、放熱用の露出サーマル パッドが付いた 8 リ ードの WSON パッケージで供給されます。このデバイス は、産業用温度範囲の -40℃~+105℃で動作が規定さ れています。

パッケージ情報

部品番号 (1)	パッケージ ⁽²⁾	パッケージ サイズ
OPA817	DTK (WSON, 8)	3mm × 3mm

- セクション 4 を参照してください。
- 詳細については、セクション 11 を参照してください。



大信号周波数応答



Table of Contents

1 特長	
2 アプリケーション	
3 概要	
4 Device Comparison Table	
5 Pin Configuration and Functions	
6 Specifications	
6.1 Absolute Maximum Ratings	4
6.2 ESD Ratings	4
6.3 Recommended Operating Conditions	4
6.4 Thermal Information	4
6.5 Electrical Characteristics	
6.6 Typical Characteristics: V _S = ±5 V	8
7 Detailed Description	14
7.1 Overview	
7.2 Functional Block Diagram	14
7.3 Feature Description	
7.4 Device Functional Modes	

o Application and implementation	
8.1 Application Information	18
8.2 Typical Applications	19
8.3 Power Supply Recommendations	
8.4 Layout	
9 Device and Documentation Support	<mark>23</mark>
9.1 Device Support	23
9.2 Documentation Support	23
9.3ドキュメントの更新通知を受け取る方法	23
9.4 サポート・リソース	23
9.5 Trademarks	23
9.6 静電気放電に関する注意事項	23
9.7 用語集	<u>23</u>
10 Revision History	23
11 Mechanical, Packaging, and Orderable	
Information	24

4 Device Comparison Table

DEVICE	SUPPLY VOLTAGE (V)	BW (MHz)	INPUT	SLEW RATE (V/μs)	VOLTAGE NOISE (nV/√Hz)	MINIMUM STABLE GAIN (V/V)
OPA817	±6.3	400	FET	1000	4.5	1
OPA818	±6.5	2700	FET	1400	2.2	7
OPA657	±5	1600	FET	700	4.8	7
OPA656	±5	230	FET	290	7	1
OPA659	±6	350	FET	2550	8.9	1
OPA858	±2.5	5500	CMOS	2000	2.5	7
THS4631	±15	210	FET	1000	7	1

5 Pin Configuration and Functions

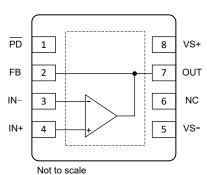


図 5-1. DTK Package, 8-Pin WSON With Thermal Pad (Top View)

表 5-1. Pin Functions

PIN			DESCRIPTION
NAME	NO.	1176	DESCRIPTION
FB	2	Output	Feedback resistor connection (optional)
IN-	3	Input	Inverting input
NC 6 — No connect (no internal of		Input	Noninverting input
NC	6	_	No connect (no internal connection to die)
OUT	7	Output	Output of amplifier
PD	1	Input	Power down Low = amplifier disabled, High = amplifier enabled, Internal 2-M Ω pullup allows floating this pin
VS-	5	Power	Negative power supply
VS+	8	Power	Positive power supply
Thermal page	1	_	Electrically isolated from the die substrate. The thermal pad can be connected to any potential between the device power supplies. However, best practice is to connect the thermal pad to a heat-spreading plane, typically ground.



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN MA	X UNIT
Vs	Total supply voltage (V _{S+} - V _{S-})	1	3 V
	Maximum dV _S /dT for supply turn-on and turn-off ⁽²⁾		1 V/µs
VI	Input voltage	V _{S-} V _S	.+ V
V _{ID}	Differential input voltage	±V	s V
II	Continuous input current	±1	0 mA
Io	Continuous output current ⁽³⁾	±3	0 mA
	Continuous power dissipation	See Thermal Information	
T _J	Maximum junction temperature	15	0 °C
T _A	Operating free-air temperature	-40 10	5 °C
T _{stg}	Storage temperature	-65 12	5 °C

⁽¹⁾ Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

- (2) To keep the edge-triggered ESD absorption devices across the supply pins off, do not exceed this specification.
- (3) Long-term continuous current for electromigration limits.

6.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	\/
V _(ESD)	discharge	Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002 ⁽²⁾	±1500	V

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V _{S+} - V _{S-}	Total supply voltage	6	10	12.6	V
T _A	Ambient temperature	-40	25	105	°C

6.4 Thermal Information

		OPA817	
	THERMAL METRIC ⁽¹⁾	DTK (WSON)	UNIT
		8 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	64.9	°C/W
R ₀ JC(top)	Junction-to-case (top) thermal resistance	53.0	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	32.8	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	1.3	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	32.8	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	9.0	°C/W

 For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

資料に関するフィードバック(ご意見やお問い合わせ)を送信

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6.5 Electrical Characteristics

at $T_A \approx 25^{\circ}C$, $V_S = \pm 5$ V, G = 1 V/V, $R_F = 0$, $R_F = 250$ Ω for other gains, $R_L = 100$ Ω , and input and output referenced to mid-supply (unless otherwise noted)

1 1) (unless otherwise noted) PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
AC DED		TEST CONDITIONS	IVIIIN	IIF	IVIAA	UNIT
AC PER	FORMANCE	V = 200 == V		000		
		$V_{OUT} = 200 \text{ mV}_{PP}$		800		
SSBW	Small-signal bandwidth	V _{OUT} = 200 mV _{PP} , G = 2 V/V		400		MHz
		V _{OUT} = 200 mV _{PP} , G = 5 V/V		100		
		V _{OUT} = 200 mV _{PP} , G = 10 V/V		40		
GBWP	Gain-bandwidth product	V _{OUT} = 200 mV _{PP} , G = 100 V/V		400		MHz
LSBW	Large-signal bandwidth	V _{OUT} = 2 V _{PP}		250		MHz
		$V_{OUT} = 4 V_{PP}$		140		
	Bandwidth for 0.1-dB flatness	V _{OUT} = 2 V _{PP}		100		MHz
SR	Slew rate (10% to 90%)	V _{OUT} = 4–V step		1000		V/µs
	Slew rate (10% to 90%)	V _{OUT} = 1–V step, Gain = 2 V/V		750		*, μ.σ
t _R , t _F	Rise, fall time	V _{OUT} = 200–mV step		0.7		ns
	Settling time to 0.1%,	V _{OUT} = 2–V step		6		ns
	Overshoot and undershoot	V _{OUT} = 2–V step		8		%
	Output Overdrive recovery time	$V_{OUT} = V_{S-}$ to V_{S+} , $G = 2 V/V$,		15		ns
	Second-order harmonic distortion	f = 1 MHz, V _{OUT} = 2 V _{PP}		-110		- dBc
LIDO		f = 10 MHz, V _{OUT} = 2 V _{PP}		-86		
HD2		f = 50 MHz, V _{OUT} = 2 V _{PP}		-76		
		$f = 10 \text{ MHz}, V_{OUT} = 2 V_{PP}, R_L = 1 \text{ k}\Omega$		– 97		
	Third-order harmonic distortion	f = 1 MHz, V _{OUT} = 2 V _{PP}		-120		
HD3		f = 10 MHz, V _{OUT} = 2 V _{PP}		-100		dBc
		f = 50 MHz, V _{OUT} = 2 V _{PP}		-68		
		$f = 10 \text{ MHz}, V_{OUT} = 2 V_{PP}, R_{L} = 1 kΩ$		-102		
	Input voltage noise	f ≥ 200 kHz		4.5		nV/√Hz
e _N	Voltage noise 1/f corner frequency			2.6		kHz
	Input current noise			18		fA/√Hz
OC PER	FORMANCE					
		V _{OUT} = ±1 V	78	85		
A _{OL}	Open-loop voltage gain	$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$	72			dB
OL	open sop comige game	$T_A = -40^{\circ}\text{C to } +105^{\circ}\text{C}$	69			
		A		50	±250	
Vos	Input-referred offset voltage	$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$			±500	μV
• 05	input referred effect vertage	$T_A = -40^{\circ}\text{C to } +105^{\circ}\text{C}$			±600	μ,
		$T_A = -40^{\circ} \text{C to } +85^{\circ} \text{C}$		1	±3.5	
	Input offset voltage drift	$T_A = -40^{\circ} \text{C to } +105^{\circ} \text{C}$		<u>.</u> 1	±3.5	μV/°C
		14 - 40 6 10 1 103 6			±20	
	Input bigg gurrent	T _A = -40°C to +85°C				m A
В	Input bias current	**			±1000	pΑ
		$T_A = -40^{\circ}C \text{ to } +105^{\circ}C$			±1500	
		T 4000 t 10500		1	±20	
os	Input offset current	$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$			±500	pA
		$T_A = -40^{\circ}\text{C to } +105^{\circ}\text{C}$			±750	
	Internal feedback trace resistance	Device turned OFF, OUT to FB pin resistance		0.7		Ω



6.5 Electrical Characteristics (続き)

at $T_A \approx 25^{\circ}C$, $V_S = \pm 5$ V, G = 1 V/V, $R_F = 0$, $R_F = 250$ Ω for other gains, $R_L = 100$ Ω , and input and output referenced to midsupply (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
INPUT			'			
			2.1	2.7		
	Most positive input voltage ⁽¹⁾	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$	2.0			V
		$T_A = -40^{\circ}C \text{ to } +105^{\circ}C$	2.0			
				-3.9	-3.5	
	Most negative input voltage ⁽¹⁾	$T_A = -40$ °C to +85°C			-3.4	V
		$T_A = -40^{\circ}C \text{ to } +105^{\circ}C$			-3.4	
		V _{CM} = ±0.5 V	84	110		
CMRR	Common-mode rejection ratio	T _A = -40°C to 85°C	83			dB
		T _A = -40°C to 105°C	82			
	Input impedance common-mode			60 2.9		GΩ pF
	Input capacitance differential mode			0.1		pF
OUTPUT	г		1			1
		no-load		-3.9	-3.6	
V	Output voltage low	R _L = 100 Ω		-3.7	-3.4	.,
V_{OL}	Output voltage, low	$T_A = -40$ °C to +85°C			-3.3	V
		$T_A = -40^{\circ}C \text{ to } +105^{\circ}C$			-3.2	
	Output voltage, high	no-load	3.7	3.9		
\/		R _L = 100 Ω	3.4	3.7		V
V _{OH}		$T_A = -40$ °C to +85°C	3.3			v
		$T_A = -40^{\circ}C \text{ to } +105^{\circ}C,$	3.2			
		V_{OUT} = ±1 V, ΔV_{OS} < 2 mV	±58	80		
	Linear output drive (sourcing/sinking)	$T_A = -40 \text{ to } 85^{\circ}\text{C}, \Delta V_{OS} < 3 \text{ mV}$	±40			mA
		$T_A = -40$ to 105°C, $\Delta V_{OS} < 3$ mV	±35			
	Short-circuit current			±100		mA
Z _O	Closed loop output Impedance	f = 100 kHz		0.04		Ω
POWER	SUPPLY					
				23.5	24.5	
I_Q	Quiescent current	$T_A = -40$ °C to +85°C			24.7	mA
		$T_A = -40^{\circ}C \text{ to } +105^{\circ}C$			24.9	
		$\Delta V_{S+} = \pm 0.5 \text{ V}$	80	100		
PSRR+	Power-supply rejection ratio	$T_A = -40$ °C to +85°C	77			dB
		$T_A = -40^{\circ}C \text{ to } +105^{\circ}C$	76			
		$\Delta V_{S-} = \pm 0.5 V$,	80	100		
PSRR-	Power-supply rejection ratio	$T_A = -40$ °C to +85°C	77			dB
		T _A = -40°C to +105°C	76			

6.5 Electrical Characteristics (続き)

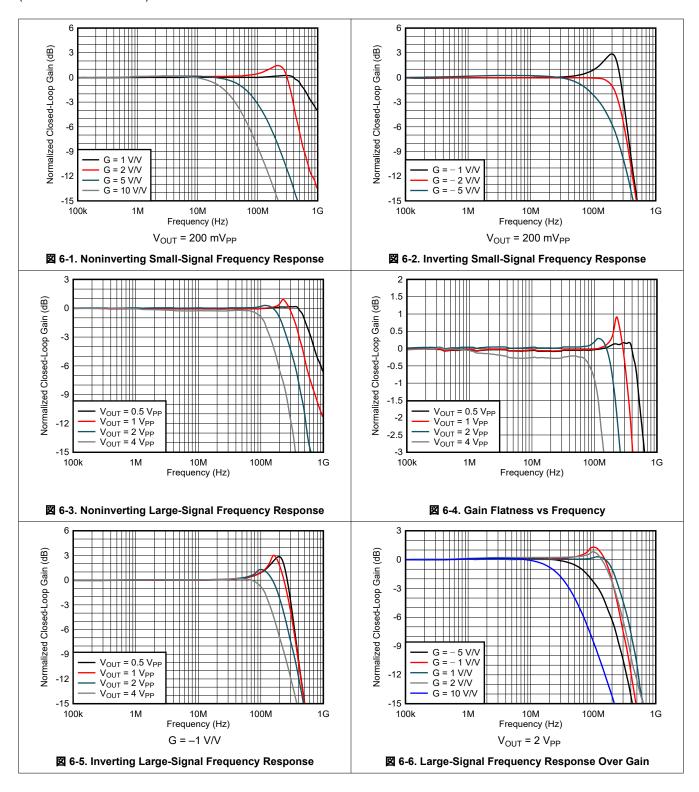
at $T_A \approx 25^{\circ}C$, $V_S = \pm 5$ V, G = 1 V/V, $R_F = 0$, $R_F = 250$ Ω for other gains, $R_L = 100$ Ω , and input and output referenced to midsupply (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
POWER DOWN				<u> </u>	
Enable voltage threshold	Specified <i>on</i> above (V _{S+}) – 1 V			4	V
Disable voltage threshold	Specified off below (V _{S+}) – 3 V	2			V
Power-down quiescent current	$\overline{PD} \le (V_{S+}) - 3V$		55	100	μΑ
Power-down pin bias current in shutdown mode	PD = 0 V to (V _{S+}) – 3 V		9	12	μΑ
Power-down pin bias current in active mode	$\overline{PD} = (V_{S+}) - 1 \text{ V to } (V_{S+})$		0.5	1	μΑ
Turn-on time delay	Time from \overline{PD} voltage exceeds threshold to V_{OUT} = 90% of final value, V_{IN} = 1V		0.3		μs
Turn-off time delay	Time from \overline{PD} voltage reduces below threshold to I_Q = 10% of active mode value		0.1		μs

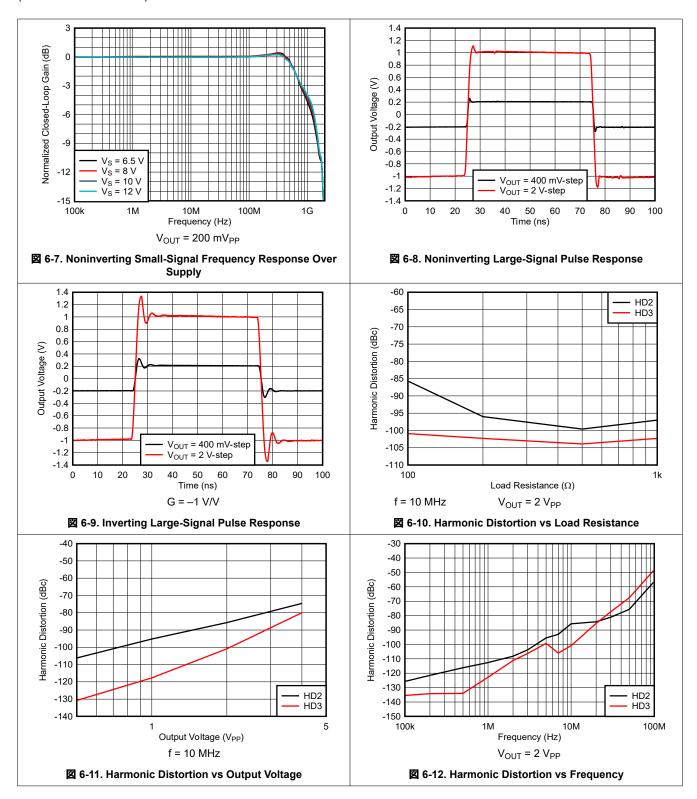
⁽¹⁾ Input range for CMRR > 77 dB.



6.6 Typical Characteristics: $V_S = \pm 5 \text{ V}$

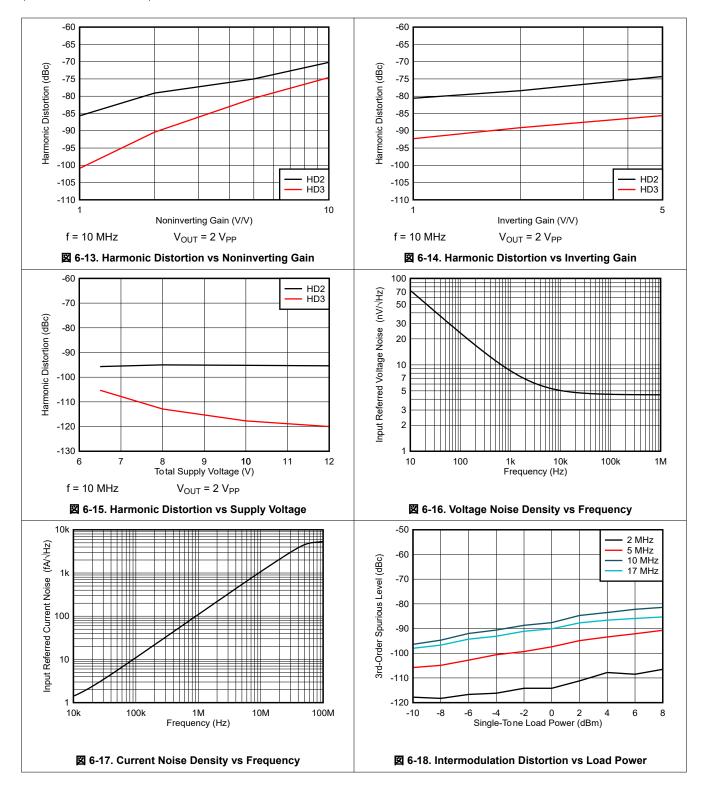


6.6 Typical Characteristics: V_S = ±5 V (continued)



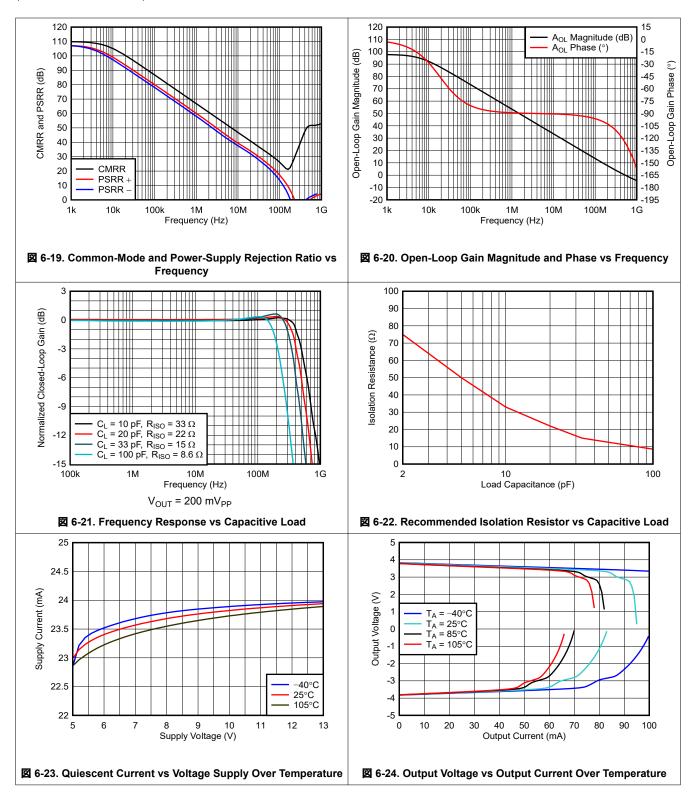


6.6 Typical Characteristics: $V_S = \pm 5 V$ (continued)



6.6 Typical Characteristics: $V_S = \pm 5 V$ (continued)

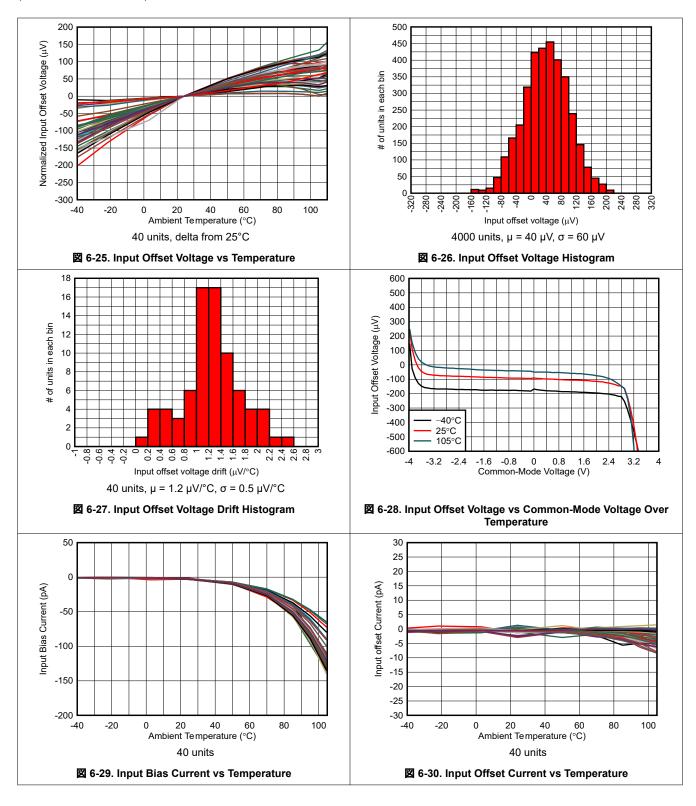
at G = 1 V/V, $R_F = 0 \Omega$, $R_F = 250 \Omega$ for other gains, $R_L = 100 \Omega$, input and output referenced to mid-supply, and $T_A \cong 25^{\circ}C$ (unless otherwise noted)



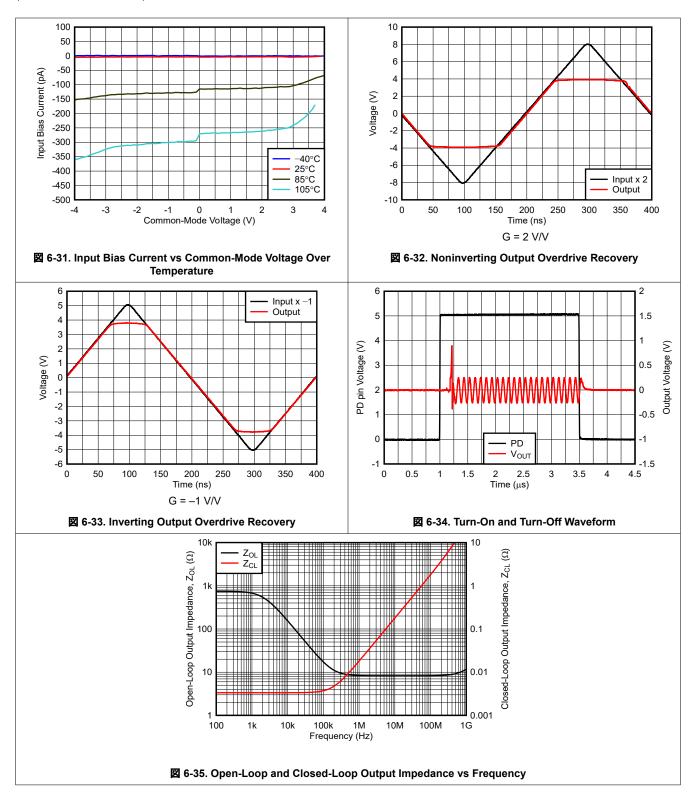
English Data Sheet: SBOS847



6.6 Typical Characteristics: $V_S = \pm 5 V$ (continued)



6.6 Typical Characteristics: V_S = ±5 V (continued)



7 Detailed Description

7.1 Overview

The OPA817 is a high-voltage, unity-gain-stable, 400-MHz gain-bandwidth product (GBWP), voltage-feedback operational amplifier (op amp) featuring a 4.5-nV/ $\sqrt{\text{Hz}}$, low-noise, JFET input stage. The low offset voltage (250 μ V maximum), offset voltage drift (3.5 μ V/°C maximum), and unity gain bandwidth of 800 MHz makes this device an excellent choice for high-input-impedance, high-speed, data-acquisition front-ends. The high voltage capability combined with 1000 V/ μ s slew rate enables applications needing wide output swings (9 V_{PP} at V_S = 12 V) for high-frequency signals such as those often found in medical instrumentation, optical front-end, test, and measurement applications. The low noise JFET input with pico-amperes of bias current makes the device attractive in high-gain TIA applications and in test and measurement front-ends. OPA817 also features a power-down mode that disables the core amplifier for power savings.

The OPA817 is built using Tl's proprietary high-voltage, high-speed, complementary bipolar SiGe process.

7.2 Functional Block Diagram

The OPA817 is a conventional voltage feedback op amp with two high-impedance inputs and a low-impedance output. \boxtimes 7-1 and \boxtimes 7-2 shows two standard amplifier configuration examples that are supported for this device. The reference voltage (V_{REF}) level shifts the dc operating point for each configuration, which is typically set to mid-supply in single-supply operation. V_{REF} is typically set to ground in split-supply applications.

$$V_{SIG}$$
 V_{REF}
 V_{S+}
 V_{S+}
 V_{REF}
 V_{S+}
 V_{REF}
 V_{REF}
 V_{S+}
 V_{REF}
 V_{S+}
 V_{REF}
 V_{REF}
 V_{REF}
 V_{REF}
 V_{REF}
 V_{REF}
 V_{REF}

図 7-1. Noninverting Amplifier

$$V_{SIG}$$
 V_{REF}
 V_{NO}
 V_{NO}

図 7-2. Inverting Amplifier

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7.3 Feature Description

7.3.1 Input and ESD Protection

The OPA817 is built using a very high-speed complementary bipolar process. The internal junction breakdown voltages are relatively low for these very small geometry devices. These breakdowns are reflected in the *Absolute Maximum Ratings*. As ☑ 7-3 shows, all device pins are protected with internal ESD protection diodes to the power supplies.

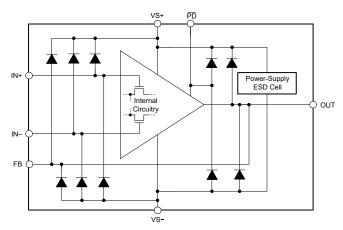


図 7-3. Internal ESD Protection

The diodes provide moderate protection to input overdrive voltages beyond the supplies as well. The protection diodes can typically support a 10-mA continuous current. Where higher currents are possible (for example, in systems with ± 12 -V supply parts driving into the OPA817), add current limiting series resistors in series with the two inputs to limit the current. Keep these resistor values as low as possible because high values degrade both noise performance and frequency response. There are no back-to-back ESD diodes between V_{IN+} and V_{IN-} . As a result, the differential input voltage between V_{IN+} and V_{IN-} is entirely absorbed by the V_{GS} of the input JFET differential pair and must not exceed the voltage ratings shown in the *Absolute Maximum Ratings*.

7.3.2 Feedback Pin

For high-speed analog design, minimizing parasitic capacitances and inductances is critical to get the best performance from a high-speed amplifier such as the OPA817. Parasitic capacitance and inductance are especially detrimental in the feedback path and at the inverting input, and result in undesired poles and zeroes in the feedback that can result in reduced phase margin or instability. Techniques used to correct this phase margin reduction often result in reduced application bandwidth. To keep system engineers from making these tradeoff choices and to simplify the PCB layout, OPA817 features an FB pin on the same side as the inverting input pin (IN–). \boxtimes 7-4 shows how this feature allows for a very short feedback resistor (R_F) connection between the FB and the IN– pin, which minimizes parasitic capacitance and inductance with minimal PCB design effort. Internally the FB pin is connected to OUT pin through metal routing on the silicon. Because of the fixed metal sizing of this connection, the FB pin has limited current carrying capability. Therefore, the specifications in the *Absolute Maximum Ratings* section must be adhered to for continuous operation. For applications requiring high accuracy, the metal routing resistance from OUT to FB can be considered and added to R_F to set the desired gain. For more information, see $\forall P > \exists V \in S$.

English Data Sheet: SBOS847



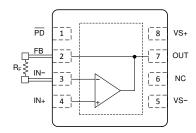
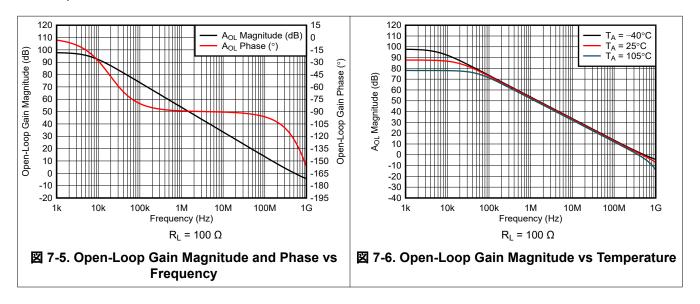


図 7-4. R_F Connection Between FB and IN- Pins

7.3.3 FET-Input Architecture With Wide Gain-Bandwidth Product

 \boxtimes 7-5 shows the open-loop gain and phase response of the OPA817. The GBWP of an op amp is measured in the 20-dB/decade constant slope region of the A_{OL} magnitude plot. The open-loop gain of 60 dB for the OPA817 is along this 20-dB/decade slope, and the corresponding frequency intercept is at 400 kHz. Converting 60 dB to linear units (1000 V/V) and multiplying by the 400-kHz frequency intercept gives a GBWP of 400 MHz for the OPA817. The A_{OL} Bode plot shows that the second pole in the A_{OL} response occurs after A_{OL} magnitude drops to less than 0 dB (1 V/V). The location of second pole results in phase change of less than 180° at 0 dB A_{OL}, indicating that the amplifier is stable in a gain of 1 V/V. Amplifiers such as the OPA817 that are JFET-input, low noise and unity-gain stable can be used as high-input-impedance buffers and gain stages with minimal degradation in SNR. The device has 800 MHz of SSBW in a gain-of-1-V/V configuration with a phase margin of approximately 55°.

The low input offset voltage and offset voltage drift of OPA817 makes the device an excellent amplifier for high-precision, high-input-impedance, wideband, data-acquisition-system front-ends. \boxtimes 8-2 shows that the system benefits from the low noise JFET input stage with pico-amperes of input bias current to achieve higher precision at 1-M Ω input impedance setting and higher SNR at 50- Ω input impedance setting simultaneously in a typical data-acquisition front-end circuit.



7.4 Device Functional Modes

7.4.1 Power-Down (PD) Pin

The OPA817 includes a power-down mode for low-power or standby operation and only consumes 55 μ A (typical) of current when placed in power-down mode. Low-power systems that are only active for small periods of time benefit from this feature. The OPA817 transitions from low-power mode to active-mode in 300 ns (typical). For power-down pin control thresholds, see also $\forall \mathcal{P} \ni \exists \mathcal{P} \ni$

Product Folder Links: OPA817

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noise coupling and false triggering. If the power-down mode is not used in an application, then connect the \overline{PD} pin to V_{S+}.

17

Product Folder Links: OPA817

8 Application and Implementation

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8.1 Application Information

8.1.1 Wideband, High-Input-Impedance DAQ Front End

The OPA817 features a unique combination of high GBWP, low-input voltage noise, and the dc precision of a trimmed JFET-input stage to provide a high input impedance for a voltage-feedback amplifier.

8-2 shows how the very high GBWP of 400 MHz and high large signal bandwidth of 250 MHz can be used to either deliver wide signal bandwidths at high gains or to extend the achievable bandwidth or gain in typical high-speed, high-input impedance data acquisition front-end applications. To achieve the full performance of the OPA817, careful attention to the printed circuit board (PCB) layout and component selection is required as discussed in the following sections of this data sheet. OPA817 also features a wider supply range thereby enabling a wider common-mode input range to support higher input signal swings.

 \boxtimes 8-1 shows the noninverting gain of +2 V/V circuit used as the basis for most of the *Typical Characteristics*. Most of the curves were characterized using signal sources with 50- Ω driving impedance, and with measurement equipment presenting a 50- Ω load impedance. As \boxtimes 8-1 shows, the 49.9- Ω shunt resistor at the V_{IN} terminal matches the source impedance of the test generator, while the 49.9- Ω series resistor at the V_O terminal provides a matching resistor for the measurement equipment load. Generally, data sheet voltage swing specifications are at the output pin (V_O in \boxtimes 8-1) while output power specifications are at the matched 50- Ω load. As shown in \boxtimes 8-1, the total 100- Ω load at the output combined with the 250- Ω total feedback network load presents the OPA817 with an effective output load of 83.3 Ω for the circuit.

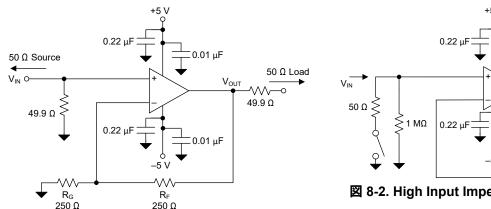


図 8-1. Noninverting G = +2 V/V Configuration and Test Circuit

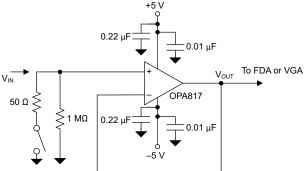


図 8-2. High Input Impedance DAQ Front-End

Voltage-feedback operational amplifiers, unlike current feedback amplifiers, can use a wide range of resistor values to set the gain. As \boxtimes 8-1 shows, always keep the parallel combination of $R_F \parallel R_G$ to a lower value to retain a controlled frequency response for the noninverting voltage amplifier. In the noninverting configuration, the parallel combination of $R_F \parallel R_G$ forms a pole with the parasitic input capacitance at the inverting node of the OPA817 (including layout parasitic capacitance). For best performance, ensure that this pole is at a frequency greater than the closed-loop bandwidth for the OPA817.

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8.2 Typical Applications

8.2.1 High-Input-Impedance, 200-MHz, Digitizer Front-End Amplifier Design

The OPA817 offers a wide large-signal bandwidth, high-slew rate along with high-input impedance making this device an excellent choice for data-acquisition systems. The trimmed dc precision of the OPA817 enables direct use of the device as a front-end amplifier where low offset and offset voltage drift is needed.

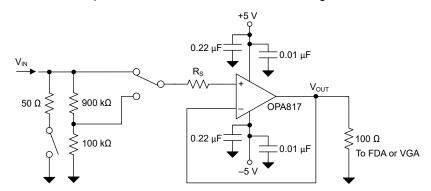


図 8-3. High-Input-Impedance, 200MHz, Digitizer Front-End Amplifier

8.2.1.1 Design Requirements

表 8-1 lists the design requirements for a high-input-impedance, 200-MHz, digitizer front-end amplifier.

& 0-1. Design Requirements								
SPECIFICATION	VALUE							
Input impedance	1 ΜΩ / 50Ω							
Input range (1 MΩ / 50 Ω)	20 V _{PP} / 2 V _{PP}							
Offset drift	3.5 μV/°C maximum							
Noise at highest resolution (50 Ω Input)	80 μV _{RMS}							

表 8-1. Design Requirements

8.2.1.2 Detailed Design Procedure

- Input Impedance: The JFET-input stage of the OPA817 offers gigaohms of input impedance, and therefore enables the front-end to be terminated with a 1-M Ω resistor while achieving excellent precision. A 50- Ω resistance can also be switched in offering matched termination for high-frequency signals. The OPA817, therefore, enables the designer to use both 1-M Ω and 50- Ω termination in the same signal chain.
- Noise: The total noise of the front-end amplifier is the function of the voltage and current noise of the OPA817, input termination, and the resistors thermal noise. In 50-Ω mode, the dominant noise source, however, is contributed by the voltage noise of the OPA817 as a result of noise being integrated over the complete bandwidth. Thus, the total RMS noise of the front-end amplifier is approximately equal to the voltage noise of OPA817 over 200 MHz.

The specified input referred voltage noise of the OPA817 is 4.5 nV/√Hz; see also セクション 6.5. The total integrated RMS noise at the input in a bandwidth of 200 MHz is given by the following equation:

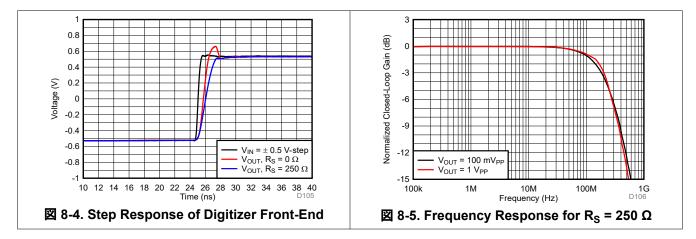
$$En_{RMS} = 4.5 \text{ nV}/\sqrt{Hz} \times \sqrt{(200 \text{ MHz} \times 1.57)} = 80 \mu V_{RMS}.$$
 (1)

The Brickwall correction factor of 1.57 is applied assuming the bandwidth is limited to 200 MHz with a single pole RC-filter before digitizing the signal with the ADC. Detailed calculations can be found at TI Precision Labs – Op Amps: Noise – Spectral Density.



• Optimizing Overshoot: The OPA817 features an internal slew-boost circuit to deliver fast rise-time in applications needing high slew rates such as when configured as a transimpedance amplifier. For applications where overshoot needs to be limited, the input slew rates can be limited with introducing a series resistance (R_S) as shown in ⋈ 8-3. The resistance R_S forms a low pass filter with the input capacitance of approximately 2.6 pF at the noninverting pin of the OPA817 limiting the input slew rate to the amplifier. ⋈ 8-4 shows how limiting the input slew rate to the amplifier results in good overshoot performance, and ⋈ 8-5 shows how this achieves a small signal and large signal bandwidth of 200 MHz.

8.2.1.3 Application Curves



8.3 Power Supply Recommendations

The OPA817 is intended to operate on supplies ranging from 6 V to 12.6 V. OPA817 supports single-supply, split, balanced, and unbalanced bipolar supplies. When operating at supplies below 8 V, consideration must be given to the input common-mode range of the amplifier. Under these supply conditions, the common-mode must be biased appropriately for linear operation. Thus, the limit to lower supply voltage operation is the usable input voltage range for the JFET-input stage.

8.4 Layout

8.4.1 Layout Guidelines

Achieving optimized performance with a high-frequency amplifier such as the OPA817 requires careful attention to board layout parasitics and external component types. Recommendations that optimize performance include the following:

1. Minimize parasitic capacitance to any ac ground for all of the signal I/O pins. Parasitic capacitance on the output and inverting input pins can cause instability. On the noninverting input, parasitic capacitance can react with the source impedance to cause unintentional bandlimiting. Ground and power metal planes act as one of the plates of a capacitor while the signal trace metal acts as the other separated by PCB dielectric. To reduce this unwanted capacitance, take care to minimize the routing of the feedback network. A plane cutout around and underneath the inverting input pin on all ground and power planes is recommended. Otherwise, ensure that ground and power planes are unbroken elsewhere on the board.

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- 2. Minimize the distance (less than 0.25-in) from the power-supply pins to high-frequency decoupling capacitors. Use high quality, 100-pF to 0.1-µF, C0G and NPO-type decoupling capacitors with voltage ratings at least three times greater than the amplifiers maximum power supplies to maintain a lowimpedance path to the amplifiers power-supply pins across the amplifiers gain bandwidth specification. At the device pins, do not allow the ground and power plane layout to be in close proximity to the signal I/O pins. Avoid narrow power and ground traces to minimize inductance between the pins and the decoupling capacitors. Use larger (2.2-µF to 6.8-µF) decoupling capacitors, effective at lower frequency, on the supply pins. Place these capacitors further from the device and share the capacitors among several devices in the same area of the PCB.
- 3. Careful selection and placement of external components preserves the high frequency performance of the OPA817. Use low-reactance resistors. Surface-mount resistors work best and allow a tighter overall layout. Never use wirewound type resistors in a high frequency application. The output pin and inverting input pin are the most sensitive to parasitic capacitance; therefore, always position the feedback and series output resistor, if any, as close as possible to the inverting input and the output pin, respectively. Place other network components, such as noninverting input termination resistors, close to the package. Even with a low parasitic capacitance at the noninverting input, high external resistor values can create significant time constants that can degrade performance. When OPA817 is configured as a conventional voltage amplifier, keep the resistor values as low as possible and consistent with the load driving considerations. Decrease the resistor values to keep the resistor noise terms low and minimizes the effect of the parasitic capacitance. However, lower resistor values increase the dynamic power consumption because R_F and R_G become part of the output load network of the amplifier.
- 4. Heat dissipation is important for a high voltage device like the OPA817 . For good thermal relief, connect the thermal pad to a heat-spreading plane that is preferably on the same layer as the OPA817, or connected by as many vias as possible if the plane is on a different layer. Have at least one heat-spreading plane on the same layer as the OPA817 that makes direct connection to the thermal pad with wide metal for good thermal conduction when operating at high ambient temperatures. If more than one heat-spreading plane is available, then connect the heat-spreading planes by a number of vias to further improve the thermal conduction.

8.4.1.1 Thermal Considerations

The OPA817 does not require a heat sink or airflow in most applications. The maximum allowed junction temperature sets the maximum allowed internal power dissipation as described in the following paragraph. Do not allow the maximum junction temperature to exceed 150°C.

Operating junction temperature (T_J) is given by $T_A + P_D \times R_{\theta JA}$. The total internal power dissipation (P_D) is the sum of quiescent power (PDQ) and additional power dissipated in the output stage (PDL) to deliver load power. Quiescent power is the specified no-load supply current times the total supply voltage across the part. PDL depends on the required output signal and load, but for a grounded resistive load, P_{DL} is at a maximum when the output is fixed at a voltage equal to 1/2 of either supply voltage (for balanced bipolar supplies). Under this condition $P_{DL} = V_S^2 / (4 \times R_L)$ where R_L includes feedback network loading.

The power in the output stage and not into the load determines internal power dissipation.

As a worst-case example, compute the maximum T_J using the OPA817 in the circuit of 🗵 8-1 operating at the maximum specified ambient temperature of +105°C and driving a grounded 100-Ω load.

$$P_D$$
 = 10 V × 23.5 mA + 5² / (4 × (100 Ω || 500 Ω)) \cong 310 mW

Maximum $T_J = 105^{\circ}C + (0.310 \text{ W} \times 64.9^{\circ}C/\text{W}) = 125.1^{\circ}C.$

All actual applications operate at lower internal power and junction temperature.

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21



8.4.2 Layout Example

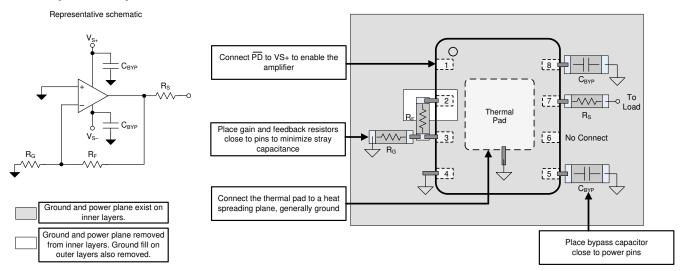


図 8-6. Layout Recommendation

English Data Sheet: SBOS847

9 Device and Documentation Support

9.1 Device Support

9.1.1 Development Support

Texas Instruments, Wide Bandwidth Optical Front-end Reference Design

9.2 Documentation Support

9.2.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, OPA817EVM User's Guide
- Texas Instruments, Transimpedance Considerations for High-Speed Amplifiers application report
- Texas Instruments, Maximizing the Dynamic Range of Analog TIA Front-End technical brief
- Texas Instruments, What You Need To Know About Transimpedance Amplifiers Part 1
- Texas Instruments, What You Need To Know About Transimpedance Amplifiers Part 2
- · Texas Instruments, Training Video: How to Design Transimpedance Amplifier Circuits
- Texas Instruments, Training Video: High-Speed Transimpedance Amplifier Design Flow

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10 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

Changes from Revision A (December 2022) to Revision B (December 2024)

Page

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23



Changes from Revision * (July 2022) to Revision A (December 2022)

Page

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable part number	Status (1)	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
OPA817DTKR	Active	Production	WSON (DTK) 8	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 105	817
OPA817DTKR.B	Active	Production	WSON (DTK) 8	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 105	817

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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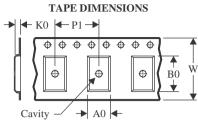
⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

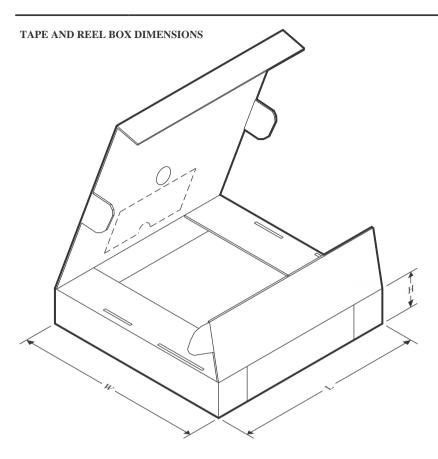


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
OPA817DTKR	WSON	DTK	8	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2

PACKAGE MATERIALS INFORMATION

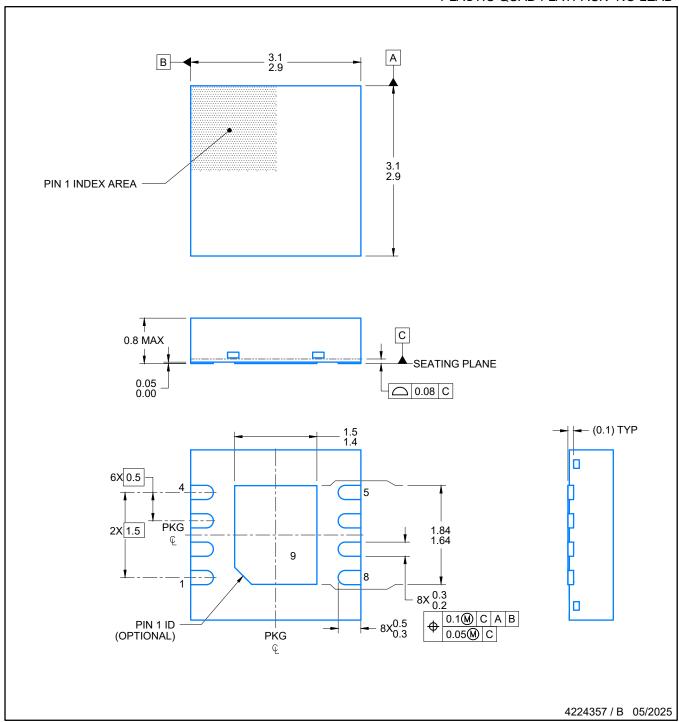
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*All dimensions are nominal

Г	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
	OPA817DTKR	WSON	DTK	8	3000	367.0	367.0	35.0

PLASTIC QUAD FLATPACK- NO LEAD

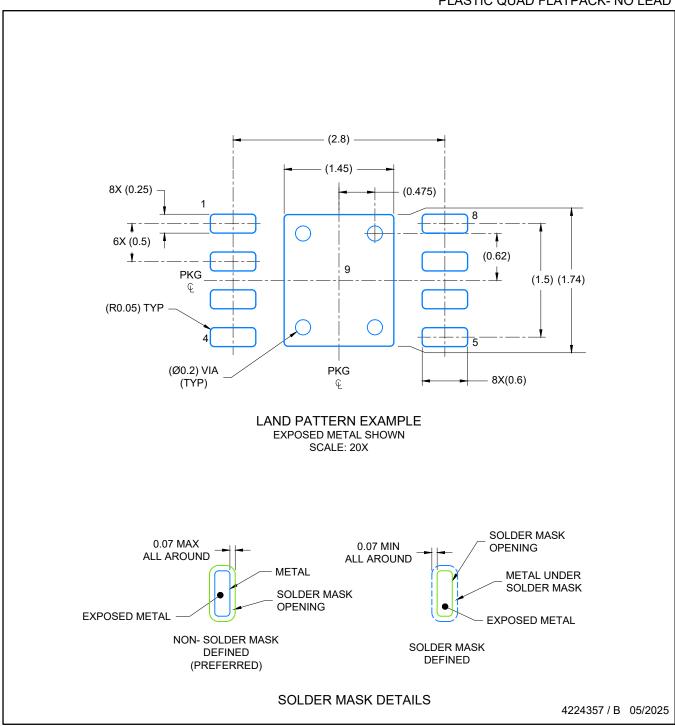


NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.



PLASTIC QUAD FLATPACK- NO LEAD



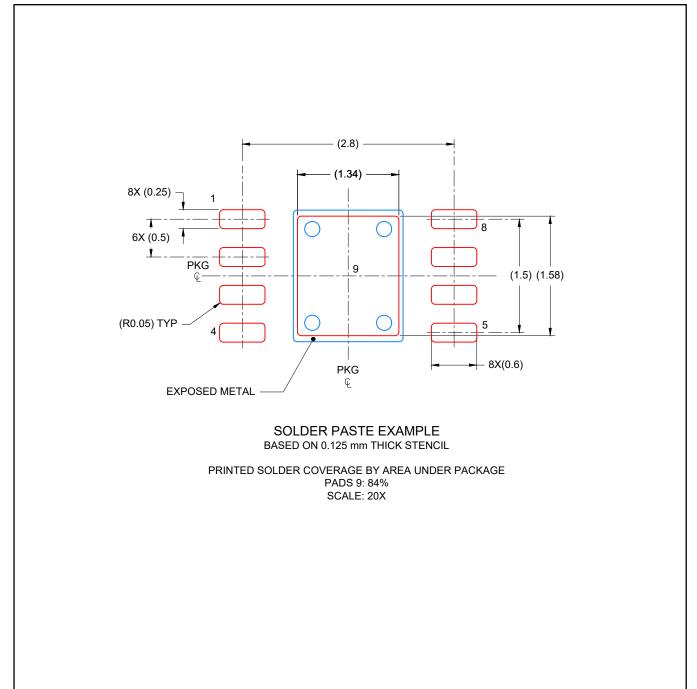
NOTES: (continued)

- 3. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271) .
- 4. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



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PLASTIC QUAD FLATPACK- NO LEAD



NOTES: (continued)

Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations..



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